

# US Patent & Trademark Office

## Patent Public Search | Text View

---

United States Patent Application Publication

20250266367

Kind Code

A1

Publication Date

August 21, 2025

Inventor(s)

WANG; Chuei-Tang et al.

---

### CHIP PACKAGE AND MANUFACTURING METHOD THEREOF

---

#### Abstract

A chip package includes a redistribution layer, at least one first semiconductor chip, an integrated fan-out package, and an insulating encapsulation. The at least one first semiconductor chip and the integrated fan-out package are electrically connected to the redistribution layer, wherein the at least one first semiconductor chip and the integrated fan-out package are located on a surface of the redistribution layer and electrically communicated to each other through the redistribution layer, and wherein the integrated fan-out package includes at least one second semiconductor chip. The insulating encapsulation encapsulates the at least one first semiconductor chip and the integrated fan-out package.

---

**Inventors:** WANG; Chuei-Tang (Taichung City, TW), Yu; Chen-Hua (Hsinchu City, TW)

**Applicant:** Taiwan Semiconductor Manufacturing Company, Ltd. (Hsinchu, TW)

**Family ID:** 1000008586736

**Assignee:** Taiwan Semiconductor Manufacturing Company, Ltd. (Hsinchu, TW)

**Appl. No.:** 19/203183

**Filed:** May 09, 2025

#### Related U.S. Application Data

parent US continuation 18303595 20230420 parent-grant-document US 12322705 child US 19203183

parent US continuation 16892271 20200603 parent-grant-document US 11676906 child US 18303595

parent US continuation 15905722 20180226 parent-grant-document US 10679947 child US 16892271

us-provisional-application US 62589533 20171121

---

## Publication Classification

**Int. Cl.:** **H01L23/538** (20060101); **H01L21/48** (20060101); **H01L21/56** (20060101); **H01L21/683** (20060101); **H01L23/00** (20060101); **H01L23/31** (20060101); **H01L25/00** (20060101); **H01L25/065** (20230101)

**U.S. Cl.:**

**CPC** **H01L23/5389** (20130101); **H01L21/4853** (20130101); **H01L21/4857** (20130101); **H01L21/565** (20130101); **H01L21/568** (20130101); **H01L21/6835** (20130101); **H01L23/3114** (20130101); **H01L23/3121** (20130101); **H01L23/5383** (20130101); **H01L23/5386** (20130101); **H01L24/19** (20130101); **H01L24/20** (20130101); **H01L25/0652** (20130101); **H01L25/0657** (20130101); **H01L25/50** (20130101); **H01L24/29** (20130101); **H01L24/32** (20130101); **H01L24/48** (20130101); **H01L24/73** (20130101); **H01L24/83** (20130101); **H01L2221/68372** (20130101); **H01L2224/18** (20130101); **H01L2224/214** (20130101); **H01L2224/2919** (20130101); **H01L2224/32145** (20130101); **H01L2224/32225** (20130101); **H01L2224/48091** (20130101); **H01L2224/48227** (20130101); **H01L2224/73265** (20130101); **H01L2224/73267** (20130101); **H01L2224/83191** (20130101); **H01L2225/0651** (20130101); **H01L2225/06524** (20130101); **H01L2225/06527** (20130101); **H01L2225/06548** (20130101); **H01L2225/06562** (20130101); **H01L2225/06582** (20130101); **H01L2924/00014** (20130101); **H01L2924/15311** (20130101); **H01L2924/181** (20130101)

---

## Background/Summary

CROSS-REFERENCE TO RELATED APPLICATION [0001] This application is a continuation application of and claims the priority benefit of a prior U.S. patent application Ser. No. 18/303,595, filed on Apr. 20, 2023, now allowed. The prior U.S. patent application Ser. No. 18/303,595 is a continuation application of and claims the priority benefits of U.S. application Ser. No. 16/892,271, filed on Jun. 3, 2020, now patented. The prior U.S. application Ser. No. 16/892,271 is a continuation application of and claims the priority benefit of a prior application Ser. No. 15/905,722, filed on Feb. 26, 2018, now patented. The prior application Ser. No. 15/905,722 claims the priority benefit of U.S. provisional application Ser. No. 62/589,533, filed on Nov. 21, 2017. The entirety of each of the above-mentioned patent applications is hereby incorporated by reference herein and made a part of this specification.

### BACKGROUND

[0002] Semiconductor devices and integrated circuits used in a variety of electronic applications, such as cell phones and other mobile electronic equipment, are typically manufactured on a single semiconductor wafer. The semiconductor chips of the wafer may be processed and packaged with other semiconductor devices, semiconductor chips, semiconductor package.

---

## Description

### BRIEF DESCRIPTION OF THE DRAWINGS

[0003] Aspects of the present disclosure are best understood from the following detailed description when read with the accompanying figures. It is noted that, in accordance with the

standard practice in the industry, various features are not drawn to scale. In fact, the dimensions of the various features may be arbitrarily increased or reduced for clarity of discussion.

[0004] FIG. 1 to FIG. 11 are schematic cross sectional views of various stages in a manufacturing method of a chip package in accordance with some exemplary embodiments of the present disclosure.

[0005] FIG. 12 is a schematic cross sectional view illustrating a semiconductor chip in accordance with some exemplary embodiments of the present disclosure.

[0006] FIG. 13 is a schematic cross sectional view illustrating an integrated fan-out package in accordance with some exemplary embodiments of the present disclosure.

[0007] FIG. 14 is a schematic cross sectional view illustrating a chip package in accordance with some exemplary embodiments of the present disclosure.

[0008] FIG. 15 is a schematic cross sectional view illustrating a chip package in accordance with some exemplary embodiments of the present disclosure.

[0009] FIG. 16 is a schematic cross sectional view illustrating a chip package in accordance with some exemplary embodiments of the present disclosure.

[0010] FIG. 17 is a schematic cross sectional view illustrating a chip package in accordance with some exemplary embodiments of the present disclosure.

[0011] FIG. 18 is a flow chart illustrating a method of forming an integrated fan-out package in accordance with some exemplary embodiments of the present disclosure.

[0012] FIG. 19 is a schematic cross sectional view illustrating a chip package in accordance with some exemplary embodiments of the present disclosure.

[0013] FIG. 20 is a schematic cross sectional view illustrating a chip package in accordance with some exemplary embodiments of the present disclosure.

[0014] FIG. 21 is a flow chart illustrating a method of forming an integrated fan-out package in accordance with some exemplary embodiments of the present disclosure.

[0015] FIG. 22 is a schematic cross sectional view illustrating a chip package in accordance with some exemplary embodiments of the present disclosure.

#### DETAILED DESCRIPTION

[0016] The following disclosure provides many different embodiments, or examples, for implementing different features of the provided subject matter. Specific examples of components and arrangements are described below to simplify the present disclosure. These are, of course, merely examples and are not intended to be limiting. For example, the formation of a first feature over or on a second feature in the description that follows may include embodiments in which the first and second features are formed in direct contact, and may also include embodiments in which additional features may be formed between the first and second features, such that the first and second features may not be in direct contact. In addition, the present disclosure may repeat reference numerals and/or letters in the various examples. This repetition is for the purpose of simplicity and clarity and does not in itself dictate a relationship between the various embodiments and/or configurations discussed.

[0017] Further, spatially relative terms, such as “beneath,” “below,” “lower,” “above,” “upper” and the like, may be used herein for ease of description to describe one element or feature's relationship to another element(s) or feature(s) as illustrated in the figures. The spatially relative terms are intended to encompass different orientations of the device in use or operation in addition to the orientation depicted in the figures. The apparatus may be otherwise oriented (rotated 90 degrees or at other orientations) and the spatially relative descriptors used herein may likewise be interpreted accordingly.

[0018] In addition, terms, such as “first,” “second,” and the like, may be used herein for ease of description to describe similar or different element(s) or feature(s) as illustrated in the figures, and may be used interchangeably depending on the order of the presence or the contexts of the description.

[0019] Other features and processes may also be included. For example, testing structures may be included to aid in the verification testing of the 3D packaging or 3DIC devices. The testing structures may include, for example, test pads formed in a redistribution layer or on a substrate that allows the testing of the 3D packaging or 3DIC, the use of probes and/or probe cards, and the like. The verification testing may be performed on intermediate structures as well as the final structure. Additionally, the structures and methods disclosed herein may be used in conjunction with testing methodologies that incorporate intermediate verification of known good dies to increase the yield and decrease costs.

[0020] FIG. 1 to FIG. 11 are schematic cross sectional views of various stages in a manufacturing method of a chip package in accordance with some exemplary embodiments of the present disclosure. In FIG. 1 to FIG. 11, a chip package 10 is shown to represent a chip package obtained following the manufacturing method, for example. In exemplary embodiments, the manufacturing method is part of a wafer level packaging process. It is to be noted that the processing steps described herein cover a portion of the manufacturing processes used to fabricate a chip package. The embodiments are intended to provide further explanations but are not used to limit the scope of the present disclosure. In FIG. 1, for example, two semiconductor chips (e.g. two semiconductor chips 110 or two semiconductor chips 120) are shown to represent plural semiconductor chips of the wafer; in addition, in FIG. 2 to FIG. 11, one semiconductor chip 160 is shown to represent single or plural semiconductor chips, and one integrated fan-out package 50a is shown to represent single or plural integrated fan-out packages, the disclosure is not limited thereto. In other embodiments, two or more semiconductor chips are shown to represent plural semiconductor chips and two or more integrated fan-out packages are shown to represent plural integrated fan-out packages, and two or more chip packages are shown to represent plural chip packages obtained following the (semiconductor) manufacturing method, the disclosure is not limited thereto.

[0021] Referring to FIG. 1, in some embodiments, a wafer 100 including semiconductor chips 110 and a wafer 200 including semiconductor chips 120 are provided, and a dicing process is performed to cut the wafer 100 and the wafer 200 along a cutting line (shown as the dotted line in FIG. 1) into individual and separated semiconductor chips 110 and individual and separated semiconductor chips 120. In one embodiment, the dicing process is a wafer dicing process. In some embodiments, the semiconductor chips 110 and the semiconductor chips 120 include low-power (LP) double data rate (DDR) memory modules, such as LPDDR1, LPDDR2, LPDDR3, LPDDR4, or the like memory modules. In one embodiment, the semiconductor chips 110 and the semiconductor chips 120 may be the same type. In an alternative embodiment, the semiconductor chips 110 and the semiconductor chips 120 may be different types. However, the disclosure is not limited thereto; in an alternative embodiment, the semiconductor chips 110 and the semiconductor chips 120 may include wireless and radio frequency (RF) chips, digital chips, analog chips or mixed signal chips, application-specific integrated circuit ("ASIC") chips, sensor chips, other memory chips, logic chips or voltage regulator chips.

[0022] In certain embodiments, each semiconductor chip 110 has an active surface 110a, contact pads 111 distributed on the active surface 110a, a protection layer 112 covering the active surface 110a and a portion of the contact pads 111, and connecting pillars 113 connected to the portion of the contact pads 111 and penetrating and protruding out of the protection layer 112. The contact pads 111 are partially exposed by the protection layer 112, and the connecting pillars 113 are disposed on and electrically connected to the contact pads 111, respectively. As shown in FIG. 1, the connecting pillars 113 protrude out of a top surface of the protection layer 112, in some embodiments. That is, a portion of each of the connecting pillars 113 is not covered or wrapped by the protection layer 112.

[0023] In certain embodiments, each semiconductor chip 120 has an active surface 120a, contact pads 121 distributed on the active surface 120a, a protection layer 122 covering the active surface 120a and a portion of the contact pads 121, and connecting pillars 123 connected to the portion of

the contact pads **121** and penetrating and protruding out of the protection layer **122**. The contact pads **121** are partially exposed by the protection layer **122**, and the connecting pillars **123** are disposed on and electrically connected to the contact pads **121**, respectively. In some embodiments, before the dicing process, a connecting film DA1 is provided to a bottom surface of the second wafer **200**. In some embodiments, the connecting film DA1 may be, for example, a semiconductor chip attach film, a layer made of adhesives or epoxy resin, or the like, the disclosure is not limited thereto. As shown in FIG. 1, the connecting pillars **123** protrude out of a top surface of the protection layer **122**, for example. That is, a portion of each of the connecting pillars **123** is not covered or wrapped by the protection layer **122**, in certain embodiments.

[0024] However, the disclosure is not limited thereto; in an alternative embodiment, for a semiconductor chip **120a**, top surfaces **123a** of the connecting pillars **123** may be substantially coplanar with a top surface **122a** of the protection layer **122**, as shown in FIG. 12. The semiconductor chip **120a** depicted in FIG. 12 is similar to the semiconductor chip **120** depicted in FIG. 1, such that the elements similar to or substantially the same as the elements described above will use the same reference numbers, and certain details or descriptions of the same elements and the relationship thereof (e.g. the relative positioning configuration and electrical connection) will not be repeated herein. Due to such configuration, the connecting pillars **123** are protected from being damaged during the transferring step of the semiconductor chip **120a**, and thereby the reliability of electrical connections in the integrated fan-out package **50a'** is further improved.

[0025] In some embodiments, the contact pads **111** and/or the contact pads **121** may be aluminum pads or other suitable metal pads. In one embodiment, the materials of the contact pads **111** and the contact pads **121** may be the same, the disclosure is not limited thereto. In an alternative embodiment, the material of the contact pads **111** is different from the material of the contact pads **121**.

[0026] In some embodiments, the protection layer **112** and/or the protection layer **122** may be a polybenzoxazole (PBO) layer, a polyimide (PI) layer or other suitable polymers. In some alternative embodiments, the protection layer **112** and/or the protection layer **122** may be made of inorganic materials, such as silicon oxide, silicon nitride, silicon oxynitride, or any suitable dielectric material. In one embodiment, the materials of the protection layer **112** and the protection layer **122** may be the same, the disclosure is not limited thereto. In an alternative embodiment, the material of the protection layer **112** is different from the material of the protection layer **122**.

[0027] In some embodiments, the connecting pillars **113** and/or the connecting pillars **123** are copper pillars, copper alloy pillar or other suitable metal pillars. In one embodiment, the materials of the connecting pillars **113** and the connecting pillars **123** may be the same, the disclosure is not limited thereto. In an alternative embodiment, the material of the connecting pillars **113** is different from the material of the connecting pillars **123**.

[0028] Referring to FIG. 2, in some embodiments, a carrier C1 is provided, the carrier C1 may be a glass carrier or any suitable carrier for the manufacturing method of the chip package. In some embodiments, the carrier C1 is provided with a debond layer DB1 and a connecting film DA2 formed thereon, where the debond layer DB1 is located between the carrier C1 and the connecting film DA2. In some embodiments, the material of the debond layer DB1 may be any material suitable for debonding the carrier C1 from the above layers (e.g. the connecting film DA2) disposed thereon. For example, the debond layer DB1 may include a release layer (such as a light-to-heat conversion ("LTHC") layer) or an adhesive layer (such as an ultra-violet curable adhesive or a heat curable adhesive layer). It may also be noted that materials for the carrier C1 and the debond layer DB1 are not limited to what are disclosed herein according to the disclosure. In certain embodiments, the materials of the connecting film DA2 and the connecting film DA1 may be the same, however the disclosure is not limited thereto. In one embodiment, the material of the connecting film DA2 may be different from the material of the connecting film DA1.

[0029] In an alternative embodiment, an insulating layer (not shown) may be formed between the

debond layer DB1 and the connecting layer DA2. For example, the insulating layer may be a polybenzoxazole (PBO) layer formed on the debond layer DB1. However, the disclosure is not limited thereto.

[0030] Referring to FIG. 2, in some embodiments, after the carrier C1 having the debond layer DB1 and the connecting film DA2 is provided, one or more semiconductor chips 110 and one or more semiconductor chips 120 depicted in FIG. 1 are picked-up and placed on the connecting film DA2 carried by the carrier C1 through the debond layer DB1. As shown in FIG. 2, for example, the semiconductor chip 110 is mechanically connected and stably adhered to the connecting film DA2, while the semiconductor chip 120 is stacked on the semiconductor chip 110 through the connecting film DA1. Due to the connecting film DA1 provided between the semiconductor chip 110 and the semiconductor chip 120, the semiconductor chip 110 and the semiconductor chip 120 are stably adhered to one another. In certain embodiments, as shown in FIG. 2, the semiconductor chip 110 and the semiconductor chip 120 are front-to-back attached.

[0031] Referring to FIG. 3, an encapsulant 130 is formed over the carrier C1 (e.g., on the connecting film DA2) to encapsulate the semiconductor chip 110 and the semiconductor chip 120. In other words, the semiconductor chip 110 and the semiconductor chip 120 are covered by and embedded in the encapsulant 130. That is, for example, the semiconductor chip 110 and the semiconductor chip 120 are not accessibly exposed by the encapsulant 130, as shown in FIG. 3. In some embodiments, the encapsulant 130 is a molding compound formed by a molding process, and the material of the encapsulant 130 may include epoxy or other suitable resins. For example, the encapsulant 130 may be epoxy resin containing inorganic filler or inorganic compound (e.g. silica, clay, and so on) which can be added therein to optimize coefficient of thermal expansion (CTE) of the encapsulant 130. The disclosure is not limited thereto.

[0032] Referring to FIG. 3 and FIG. 4, in some embodiments, the encapsulant 130 is planarized to form an encapsulant 130' exposing the semiconductor chip 110 and the semiconductor chip 120. In certain embodiments, as shown in FIG. 4, after the planarization, top surfaces 113a of the connecting pillars 113 of the semiconductor chip 110 and top surfaces 123a of the connecting pillars 123 of the semiconductor chip 120 are accessibly exposed by a top surface 130a' of the encapsulant 130'. That is, for example, the top surfaces 113a of the connecting pillars 113 of the semiconductor chip 110 and the top surfaces 123a of the connecting pillars 123 of the semiconductor chip 120 become substantially leveled with the top surface 130a' of the encapsulant 130'. In other words, the top surfaces 113a of the connecting pillars 113 of the semiconductor chip 110, the top surfaces 123a of the connecting pillars 123 of the semiconductor chip 120, and the top surface 130a' of the encapsulant 130' are substantially coplanar to each other.

[0033] The encapsulant 130 may be planarized by mechanical grinding or chemical mechanical polishing (CMP), for example. After the planarizing step, a cleaning step may be optionally performed, for example to clean and remove the residue generated from the planarizing step. However, the disclosure is not limited thereto, and the planarizing step may be performed through any other suitable method.

[0034] In some embodiments, during planarizing the encapsulant 130, the connecting pillars 113 of the semiconductor chip 110 and the connecting pillars 123 of the semiconductor chip 120 may also be planarized. In certain embodiments, the planarizing step may, for example, performed on the over-molded encapsulant 130 to level the top surface 130a' of the encapsulant 130', the top surfaces 113a of the connecting pillars 113 of the semiconductor chip 110, and the top surfaces 123a of the connecting pillars 123 of the semiconductor chip 120.

[0035] Referring to FIG. 5, in some embodiments, a redistribution layer 140 and conductive features 150 are sequentially formed on the encapsulant 130', the semiconductor chip 110, and the semiconductor chip 120. As shown in FIG. 5, the redistribution layer 140 is formed on the top surface 130a' of the encapsulant 130', the top surfaces 113a of the connecting pillars 113 of the semiconductor chip 110, and the top surfaces 123a of the connecting pillars 123 of the

semiconductor chip **120**. In some embodiments, the redistribution layer **140** is electrically connected to the semiconductor chip **110** through the connecting pillars **113** and is electrically connected to the semiconductor chip **120** through the connecting pillars **123**. As shown in FIG. 5, for example, the redistribution layer **140** is referred as a front-side redistribution layer of the semiconductor chip **110** and the semiconductor chip **120**, which provides a routing function for the semiconductor chip **110** and the semiconductor chip **120**.

[0036] In some embodiments, the formation of the redistribution layer **140** includes sequentially forming one or more polymer dielectric layers **142** and one or more metallization layers **144** in alternation. In certain embodiments, as shown in FIG. 5, the metallization layers **144** are sandwiched between the polymer dielectric layers **142**, but the top surface of the topmost layer of the metallization layers **144** is exposed by the topmost layer of the polymer dielectric layers **142** to connect the conductive features **150**, and the lowest layer of the metallization layers **144** is exposed by the lowest layer of the polymer dielectric layers **142** to connect the connecting pillars **113** of the semiconductor chip **110** and the connecting pillars **123** of the semiconductor chip **120**.

[0037] In some embodiments, the material of the polymer dielectric layers **142** includes polyimide, epoxy resin, acrylic resin, phenol resin, benzocyclobutene (BCB), polybenzoxazole (PBO), or any other suitable polymer-based dielectric material, and the polymer dielectric layers **142** may be formed by coating. In some embodiments, the material of the metallization layers **144** includes aluminum, titanium, copper, nickel, tungsten, and/or alloys thereof, and the metallization layers **144** may be formed by electroplating or deposition. However, it should be noted that the redistribution layer **140** is not limited to include three polymer dielectric layers and/or three metallization layers.

[0038] Continued on FIG. 5, in some embodiments, the conductive features **150** are formed on the redistribution structure **140**. In certain embodiments, the conductive features **150** are formed on the exposed top surface of the topmost layer of the metallization layers **144** of the redistribution structure **140** for electrically connecting with conductive elements (e.g. a connecting module or the like) and/or semiconductor elements (e.g., passive components or active components). In one embodiment, the conductive features **150** may be formed by forming a mask pattern (not shown) covering the redistribution layer **140** with openings exposing the exposed lowest layer of the metallization layers **144** of the redistribution layer **140**, forming a metallic material filling the openings to form the conductive features **150** by electroplating or deposition, and then removing the mask pattern. In one embodiment, the material of the conductive features **150** may include a metal material such as copper or copper alloys, or the like. However, the disclosure is not limited thereto. As shown in FIG. 5, for example, the exposed lowest layer of the metallization layers **144** of the redistribution layer **140** is mechanically and electrically connected to the connecting pillars **113** of the semiconductor chip **110** and the connecting pillars **123** of the semiconductor chip **120**, and the exposed top surface of the topmost layer of the metallization layers **160b** is mechanically and electrically connected to the conductive features **150**. In some embodiments, through the redistribution layer **140**, some of the conductive features **150** are electrically connected to the semiconductor chip **110**, and some of the conductive features **150** are electrically connected to the semiconductor chip **120**.

[0039] Referring to FIG. 6, in some embodiments, the carrier **C1** is debonded from the connecting film **DA2** to form the integrated fan-out package **50a**. In one embodiment, the debonding process is a laser debonding process. The connecting film **DA2** is easily separated from the carrier **C1** due to the debond layer **DB1**. In some embodiments, the connecting film **DA2** is debonded from the carrier **C1**, the carrier **C1** and the debond layer **DB1** are removed, and the connecting film **DA2** are exposed. Up to here, the manufacture of the integrated fan-out package **50a** is completed.

[0040] In some embodiments, prior to debonding the carrier **C1**, a dicing process is performed to cut a plurality of the integrated fan-out packages **50a** connected to one another into individual and separated integrated fan-out packages **50a**. For example, during the debonding step, a holding

device (not shown) is adopted to secure a position of the plurality of the integrated fan-out packages **50a** connected to one another before debonding the carrier **C1** and the debond layer **DB1**, where the conductive features **150** are held by the holding device. For example, the holding device may be an adhesive tape, a carrier film or a suction pad.

[0041] In some embodiments, prior to releasing the conductive features **150** from the holding device, the dicing process is performed to cut the plurality of the integrated fan-out packages **50a** connected to one another into individual and separated integrated fan-out packages **50a**. In one embodiment, the dicing process is a wafer dicing process including mechanical blade sawing or laser cutting. The disclosure is not limited thereto.

[0042] However, the disclosure is not limited thereto; in some alternative embodiments, as shown in FIG. 13, an integrated fan-out package **50a'** similar to the integrated fan-out package **50a** depicted in FIG. 6 is demonstrated, where the integrated fan-out package **50a'** includes the semiconductor chip **120a** (of FIG. 13) instead of the semiconductor chip **120** included in the integrated fan-out package **50a**. The elements similar to or substantially the same as the elements described above will use the same reference numbers, and certain details or descriptions of the same elements and the relationship thereof (e.g. the relative positioning configuration and electrical connection) are not repeated herein. As shown in FIG. 13, the connecting pillars **123** of the semiconductor chip **120a** are not in physical contact with the encapsulant **130'**, for example. In some embodiments, the top surfaces of the connecting pillars **113** of the semiconductor chip **110**, the top surfaces of the protection layer **122** and the connecting pillars **123** of the semiconductor chip **120a**, the top surface of the encapsulant **130'** are substantially levelled with and coplanar to each other.

[0043] Referring to FIG. 7, in some embodiments, at least one semiconductor chip **160** is provided. As shown in FIG. 7, for example, the integrated fan-out package **50a** depicted in FIG. 6 and the semiconductor chip **160** are picked up and placed on a carrier **C2** with a debond layer **DB2** and a connecting film **DA3** formed thereon, where the debond layer **DB2** is located between the carrier **C2** and the connecting film **DA3**. In some embodiments, the carrier **C2** may be a glass carrier or any suitable carrier for the manufacturing method of the chip package. In some embodiments, the material of the debond layer **DB2** may be any material suitable for debonding the carrier **C2** from the above layers (e.g. the connecting film **DA3**) disposed thereon. For example, the debond layer **DB2** may include a release layer (such as a LTHC layer) or an adhesive layer (such as an ultra-violet curable adhesive or a heat curable adhesive layer). In some embodiments, the connecting film **DA3** may be, for example, a semiconductor chip attach film, a layer made of adhesives or epoxy resin, or the like, the disclosure is not limited thereto. In one embodiment, the materials of the carrier **C1** and the carrier **C2** may be the same or different, and the materials of the debond layer **DB1** and the debond layer **DB2** may be the same or different, and/or the materials of the connecting film **DA1**, the connecting film **DA2**, and the connecting film **DA3** may be the same or different; the disclosure is not limited thereto.

[0044] In an alternative embodiment, an insulating layer (not shown) may be formed between the debond layer **DB2** and the connecting layer **DA3**. For example, the insulating layer may be a polybenzoxazole (PBO) layer formed on the debond layer **DB2**. However, the disclosure is not limited thereto. Due to the connecting layer **DA3**, the semiconductor chip **160** and the integrated fan-out package **50a** are stably adhered to the debond layer **DB2**.

[0045] In certain embodiments, the semiconductor chip **160** has an active surface **160a**, contact pads **161** distributed on the active surface **160a**, a protection layer **162** covering the active surface **160a** and a portion of the contact pads **161**, and connecting pillars **163** connected to the portion of the contact pads **161** and penetrating through the protection layer **162**. The portion of the contact pads **161** are partially exposed by the protection layer **162**, and the connecting pillars **163** are disposed on and electrically connected to the contact pads **161**, respectively. As shown in FIG. 7, for example, top surfaces **163a** of the connecting pillars **163** is substantially coplanar with a top



surface **162a** of the protection layer **162**. In some embodiments, the contact pads **161** may be aluminum pads or other suitable metal pads. In some embodiments, the protection layer **162** may be a polybenzoxazole (PBO) layer, a polyimide (PI) layer or other suitable polymers. In some alternative embodiments, the protection layer **162** may be made of inorganic materials, such as silicon oxide, silicon nitride, silicon oxynitride, or any suitable dielectric material. In some embodiments, the connecting pillars **163** are copper pillars, copper alloy pillar or other suitable metal pillars.

[0046] As shown in FIG. 7, only one semiconductor chip **160** is presented for illustrative purposes; however, it should be noted that one or more semiconductor chips may be provided. In some embodiments, the semiconductor chip **160** described herein is referred as a logic chip. In some embodiments, the semiconductor chip **160** may further include additional chip(s) of the same type or different types. For example, in an alternative embodiment, more than one semiconductor chip **160** are provided, and the semiconductor chips **160**, except for including at least one logic chip, may include the same or different types of chips selected from digital chips, analog chips or mixed signal chips, application-specific integrated circuit (“ASIC”) chips, wireless and radio frequency (RF) chips, sensor chips, memory chips, or voltage regulator chips. The disclosure is not limited thereto.

[0047] Referring to FIG. 8, in some embodiments, an insulating encapsulation **170** is formed over the carrier C2 (e.g., on the connecting film DA3) to encapsulate the semiconductor chip **160** and the integrated fan-out package **50a**. In other words, the insulating encapsulation **170** at least fills the gaps between the conductive features **150** of the integrated fan-out package **50a** and between the semiconductor chip **160** and the integrated fan-out package **50a**, where the semiconductor chip **160** and the integrated fan-out package **50a** are covered by and embedded in the insulating encapsulation **170**. That is, for example, the semiconductor chip **160** and the integrated fan-out package **50a** are not accessibly exposed by the insulating encapsulation **170**, as shown in FIG. 8. In some embodiments, the insulating encapsulation **170** is a molding compound formed by a molding process, and the material of the insulating encapsulation **170** may include epoxy or other suitable resins. For example, the insulating encapsulation **170** may be epoxy resin containing inorganic filler or inorganic compound (e.g. silica, clay, and so on) which can be added therein to optimize coefficient of thermal expansion (CTE) of the insulating encapsulation **170**. The disclosure is not limited thereto. In one embodiment, the materials of the encapsulants **130/130'** and the insulating encapsulation **170** are the same. In an alternative embodiment, the material of the insulating encapsulation **170** is different from the encapsulants **130/130'**.

[0048] Referring to FIG. 9, in some embodiments, the insulating encapsulation **170** is planarized to form an insulating encapsulation **170'** exposing the semiconductor chip **160** and the integrated fan-out package **50a**. In certain embodiments, as shown in FIG. 9, after the planarization, top surfaces **163a** of the connecting pillars **163** of the semiconductor chip **160** and top surfaces **150a** of the conductive features **150** of the integrated fan-out package **50a** are accessibly exposed by a top surface **170a'** of the insulating encapsulation **170'**. That is, for example, the top surfaces **163a** of the connecting pillars **163** of the semiconductor chip **160** and the top surfaces **150a** of the conductive features **150** of the integrated fan-out package **50a** become substantially leveled with the top surface **170a'** of the insulating encapsulation **170'**. In other words, the top surfaces **163a** of the connecting pillars **163** of the semiconductor chip **160**, the top surfaces **150a** of the conductive features **150** of the integrated fan-out package **50a**, and the top surface **170a'** of the insulating encapsulation **170'** are substantially coplanar to each other. Due to the integrated fan-out package **50b** and the semiconductor chip **160** are both encapsulated in the insulating encapsulation **170'**, a thickness of the chip package **10** is significantly reduced.

[0049] For example, the insulating encapsulation **170** may be planarized by mechanical grinding or CMP. After the planarizing step, a cleaning step may be optionally performed, for example to clean and remove the residue generated from the planarizing step. However, the disclosure is not limited

thereto, and the planarizing step may be performed through any other suitable method. In some embodiments, during planarizing the insulating encapsulation **170**, the connecting pillars **163** of the semiconductor chip **160** and the conductive features **150** of the integrated fan-out package **50a** may also be planarized. In certain embodiments, the planarizing step may, for example, be performed on the over-molded insulating encapsulation **170** to level the top surface **170a'** of the insulating encapsulation **170'**, the top surfaces **163a** of the connecting pillars **163** of the semiconductor chip **160**, and the top surfaces **150a** of the conductive features **150** of the integrated fan-out package **50a**. As shown in FIG. 9, in some embodiments, the connecting pillars **163** of the semiconductor chip **160** is separated from the insulating encapsulation **170'** by the protection layer **162**, and the conductive features **150** of the integrated fan-out package **50a** are partially wrapped by the insulating encapsulation **170'**. That is, the sidewalls of the conductive features **150** are in physical contact with the insulating encapsulation **170'**.

[0050] Referring to FIG. 10, in some embodiments, a redistribution layer **180** is formed on the insulating encapsulation **170'**, the semiconductor chip **160**, and the integrated fan-out package **50a**. As shown in FIG. 10, the redistribution layer **180** is formed on the top surface **170a'** of the insulating encapsulation **170'**, the top surfaces **163a** of the connecting pillars **163** of the semiconductor chip **160**, the top surfaces **150a** of the conductive features **150** of the integrated fan-out package **50a**. In some embodiments, the redistribution layer **180** is electrically connected to the semiconductor chip **160** through the connecting pillars **163** and is electrically connected to the integrated fan-out package **50a** through the conductive features **150**. As shown in FIG. 10, for example, the redistribution layer **180** is referred as a front-side redistribution layer of the semiconductor chip, which provides a routing function for the semiconductor chip **160** and the integrated fan-out package **50a**.

[0051] In some embodiments, the formation of the redistribution layer **180** includes sequentially forming one or more polymer dielectric layers **182** and one or more metallization layers **184** in alternation. In certain embodiments, as shown in FIG. 10, the metallization layers **184** are sandwiched between the polymer dielectric layers **182**, but the top surface of the topmost layer of the metallization layers **184** is exposed by the topmost layer of the polymer dielectric layers **182**, and the lowest layer of the metallization layers **184** is exposed by the lowest layer of the polymer dielectric layers **182** to connect the connecting pillars **163** of the semiconductor chip **160** and the conductive features **150** of the integrated fan-out package **50a**. The materials and formations of the polymer dielectric layers **182** and the polymer dielectric layers **142** may be the same or different, for example. The materials and formations of the metallization layers **184** and the metallization layers **144** may be the same or different, for example. Additionally, it should be noted that the redistribution layer **180** is not limited to include four polymer dielectric layers and/or three metallization layers.

[0052] In some embodiments, the semiconductor chip **160** is electrically connected to the semiconductor chip **110** through the redistribution layer **180**, some of the conductive features **150**, the redistribution layer **140**, the connecting pillars **113**, and the connecting pads **111**, and is electrically connected to the semiconductor chip **120** through the redistribution layer **180**, some of the conductive features **150**, the redistribution layer **140**, the connecting pillars **123**, and the connecting pads **121**. Through the redistribution layer **180**, the integrated fan-out package **50a** and the semiconductor chip **160** are electrically communicated to each other. With such configuration, a shorter electrical connection path from the semiconductor chip **160** to the integrated fan-out package **50a** is achieved; the chip package **10** has better electrical performance.

[0053] Continued on FIG. 10, in some embodiments, a plurality of under-ball metallurgy (UBM) patterns **190** is formed on the exposed top surface of the topmost layer of the metallization layers **184** of the redistribution structure **180** for electrically connecting with conductive elements (e.g. conductive balls) and/or semiconductor elements (e.g., passive components or active components). As shown in FIG. 10, for example, the redistribution layer **180** includes a front-side redistribution

layer structure having the lowest layer of the metallization layers **184** physically and electrically connected to the semiconductor chip **160** and the integrated fan-out package **50a**, and the exposed top surface of the topmost layer of the metallization layers **184** physically and electrically connected to the UBM patterns **190** for assisting ball mounting. In some embodiments, the material of the UBM patterns **190**, for example, may include copper, nickel, titanium, tungsten, or alloys thereof or the like, and may be formed by an electroplating process, for example. As shown in FIG. **10**, only eight UBM patterns **190** are presented in FIG. **10** for illustrative purposes, however, it should be noted that less than or more than eight UBM patterns **190** may be formed based on the demand; the disclosure is not limited thereto.

[0054] As shown in FIG. **10**, in some embodiments, conductive elements **200** are formed on and electrically connected to the redistribution layer **180**. In one embodiment, the conductive elements **200** are formed on the redistribution layer **180** through the UBM patterns **190**. That is, the UBM patterns **190** are located between the redistribution layer **180** and the conductive elements **200**, respectively. In some embodiments, some of the conductive elements **200** are electrically connected to the semiconductor chip **160** through some of the UBM patterns **190** and the redistribution layer **180**, and some of the conductive elements **200** are electrically connected to the integrated fan-out package **50a** through some of the UBM patterns **190** and the redistribution layer **180**. In certain embodiments, some of the conductive elements **200** are electrically connected to the semiconductor chip **110** or the semiconductor chip **120** through some of the UBM patterns **190**, the redistribution layer **180**, the respective conductive features **150**, and the redistribution layer **140**. In some embodiments, the conductive elements **200** are attached to the UBM patterns **190** through a solder flux. In some embodiments, the conductive elements **200** are, for example, solder balls or ball grid array (BGA) balls. In some embodiments, the conductive elements **200** may be disposed on the UBM patterns **190** by ball placement process or reflow process. In some embodiments, the redistribution layer **180** is located between the conductive elements **200** and the integrated fan-out package **50a**, between the conductive elements **200** and the semiconductor chip **160**, and between the conductive elements **200** and the insulating encapsulation **170**.

[0055] As shown in FIG. **10**, in some embodiments, a pitch P1 between two adjacent conductive features **150** of the conductive features **150** is less than a pitch P2 between two adjacent conductive elements **200** of the conductive elements **200**. In some embodiments, a pitch P2 between two adjacent connecting pillars **163** of the connecting pillars **163** is less than the pitch P2 between two adjacent conductive elements **200** of the conductive elements **200**. In some embodiments, the pitch P1 between two adjacent conductive features **150** of the conductive features **150** may be substantially equal to the pitch P2 between two adjacent connecting pillars **163** of the connecting pillars **163**. In one embodiment, the pitch P1 between two adjacent conductive features **150** of the conductive features **150** may be greater than or less than the pitch P2 between two adjacent connecting pillars **163** of the connecting pillars **163**, the disclosure is not limited thereto.

[0056] In an alternative embodiment, the UBM patterns **190** may be omitted, the disclosure is not limited thereto. In such embodiment, the conductive elements **200** are mechanically and electrically connected to the exposed top surface of the topmost layer of the metallization layers **184**, and parts of the topmost layer of the metallization layers **184** underlying the conductive elements **200** function as UBM layers. Additionally, solder paste (not shown) or flux may optionally apply onto the exposed top surface of the topmost layer of the metallization layers **184**, so that the conductive elements **200** are better fixed to the exposed top surface of the topmost layer of the metallization layers **184**, however the disclosure is not limited thereto.

[0057] Referring to FIG. **11**, in some embodiments, the carrier C2 is debonded from the connecting film DA3 to form the chip package **10**. In one embodiment, the debonding process is a laser debonding process. The connecting film DA3 is easily separated from the carrier C3 due to the debond layer DB2. In some embodiments, the connecting film DA3 is debonded from the carrier C2, the carrier C2 and the debond layer DB2 are removed, and the connecting film DA3 are

exposed. Up to here, the manufacture of the chip package **10** is completed. In an alternative embodiment, the connecting film **DA3** may be further removed to expose the insulating encapsulation **170'**, the semiconductor chip **160**, and the integrated fan-out package **50a**; however, the disclosure is not limited thereto.

[0058] In some embodiments, prior to debonding the carrier **C2**, a dicing process is performed to cut a plurality of the chip packages **10** connected to one another into individual and separated chip packages **10**. For example, during the debonding step, a holding device (not shown) is adopted to secure a position of the plurality of the chip packages **10** connected to one another before debonding the carrier **C2** and the debond layer **DB2**, where the conductive elements **200** are held by the holding device. For example, the holding device may be an adhesive tape, a carrier film or a suction pad.

[0059] In some embodiments, prior to releasing the conductive elements **200** from the holding device, the dicing process is performed to cut the plurality of the chip packages **10** connected to one another into individual and separated chip packages **10**. In one embodiment, the dicing process is a wafer dicing process including mechanical blade sawing or laser cutting.

[0060] However, the disclosure is not limited thereto. In some embodiments, a chip package **10'** depicted in FIG. **14** is similar to the chip package **10** depicted in FIG. **11**, such that the elements similar to or substantially the same as the elements described above will use the same reference numbers, and certain details or descriptions of the same elements and the relationship thereof (e.g. the relative positioning configuration and electrical connection) will not be repeated herein. Referring to the chip package **10** depicted in FIG. **11** and the chip package **10'** depicted in FIG. **14** together, the chip package **10'** further includes an additional element, a protection layer **PL**. In some embodiments, the protection layer **PL** is formed on the integrated fan-out package **50a** to wrap at least sidewalls **150S** of the conductive features **150**. In such embodiments, the top surfaces **150a** of the conductive features **150** and a top surface of the protection layer **PL** are substantially coplanar with the top surface **170a'** of the insulating encapsulation **170'**, as shown in FIG. **14**. As shown in FIG. **14**, the conductive features **150** of the integrated fan-out package **50a** are not in physical contact with the insulating encapsulation **170'**, for example. Due to the protection layer **PL**, the conductive features **150** are protected from being damaged during the transferring step of the integrated fan-out package **50a**, and thereby the reliability of electrical connections in the chip package **10'** is further improved. The material of the protection layer **PL** may be the same as or different from the materials of the protection layer **112** and/or the protection **122**, and thus are not repeated herein.

[0061] In certain embodiments, a chip package **10''** depicted in FIG. **15** is similar to the chip package **10** depicted in FIG. **11**, where the elements similar to or substantially the same as the elements described above will use the same reference numbers, and certain details or descriptions of the same elements and the relationship thereof (e.g. the relative positioning configuration and electrical connection) is not repeated herein. Referring to FIG. **11** and FIG. **15** together, the difference is that, for the chip package **10''** depicted in FIG. **15**, the chip package **10''** includes the integrated fan-out package **50a'** instead of the integrated fan-out package **50a** included in the chip package **10**.

[0062] In some alternative embodiments, a chip package **10'''** depicted in FIG. **16** is similar to the chip package **10'** depicted in FIG. **14**, where the elements similar to or substantially the same as the elements described above will use the same reference numbers, and certain details or descriptions of the same elements and the relationship thereof (e.g. the relative positioning configuration and electrical connection) is not repeated herein. Referring to FIG. **14** and FIG. **16** together, the difference is that, for the chip package **10'''** depicted in FIG. **16**, the chip package **10'''** includes the integrated fan-out package **50a'** instead of the integrated fan-out package **50a** included in the chip package **10**. Due to such configuration, the connecting pillars **123** are protected from being damaged during the transferring step of the semiconductor chip **120a**, and thereby the reliability of

electrical connections in the integrated fan-out packages **50a'** of the chip package **10''** and **10'''** is further improved.

[0063] FIG. **17** is a schematic cross sectional view illustrating a chip package in accordance with some exemplary embodiments of the present disclosure. FIG. **18** is a flow chart illustrating a method of forming an integrated fan-out package in accordance with some exemplary embodiments of the present disclosure. Referring to FIG. **11** and FIG. **17** together, the chip package **10** depicted in FIG. **11** and the chip package **20** depicted in FIG. **17** are similar; such that the elements similar to or substantially the same as the elements described above will use the same reference numbers, and certain details or descriptions of the same elements and the relationship thereof (e.g. the relative positioning configuration and electrical connection) will not be repeated herein. Referring to FIG. **11** and FIG. **17** together, the difference is that, for the chip package **20** depicted in FIG. **17**, the chip package **20** includes an integrated fan-out package **50b** instead of the integrated fan-out package **50a** included in the chip package **10**.

[0064] In some embodiments, the chip package **20** includes a semiconductor chip **160**, an insulating encapsulation **170'**, a redistribution layer **180**, UBM patterns **190**, and conductive element **200** in addition to the integrated fan-out package **50b**.

[0065] As shown in FIG. **17**, the integrated fan-out package **50b** includes a semiconductor chip **110'**, a semiconductor chip **120'**, an encapsulant **130'**, a redistribution layer **140**, conductive features **150**, and wirings WR1, WR2. As shown in FIG. **17**, for example, the semiconductor chip **110'** and the semiconductor chip **120'** are disposed on the redistribution layer **140**, are respectively electrically connected to the redistribution layer **140** through the wiring WR1 and the wiring WR2, and are encapsulated in the encapsulant **130'**. In some embodiments, the conductive features **150** are disposed on and electrically connected to the redistribution layer **140**, where the redistribution layer **140** is located between the conductive features **150** and the encapsulant **130'**. That is, the conductive features **150** are exposed by the encapsulant **130'**. In certain embodiments, through the redistribution layer **140**, some of the conductive features **150** are electrically connected to the semiconductor chip **110'**, and some of the conductive features **150** are electrically connected to the semiconductor chip **120'**. In certain embodiments, the integrated fan-out package **50b** further includes a connecting film DA1 provided between the semiconductor chip **110'** and the semiconductor chip **120'**, and a connecting film DA2 provided between the semiconductor chip **110'** and the redistribution layer **140**. Due to the connecting film DA1, the semiconductor chip **120'** is stably adhered to the semiconductor chip **110'**; and due to the connecting film DA2, the semiconductor chip **110'** is stably adhered to the redistribution layer **140**.

[0066] In some embodiments, the semiconductor chip **110'** and/or the semiconductor chip **120'** include low-power (LP) double data rate (DDR) memory modules, such as LPDDR1, LPDDR2, LPDDR3, LPDDR4, or the like memory modules. However, the disclosure is not limited thereto; in an alternative embodiment, the semiconductor chip **110'** and/or the semiconductor chip **120'** may include wireless and radio frequency (RF) chips, digital chips, analog chips or mixed signal chips, application-specific integrated circuit ("ASIC") chips, sensor chips, other memory chips, logic chips or voltage regulator chips. In one embodiment, the semiconductor chip **110'** and the semiconductor chip **120'** may be the same type. In an alternative embodiment, the semiconductor chip **110'** and the semiconductor chip **120'** may be different types.

[0067] In some embodiments, the semiconductor chip **160** includes an active surface **160a**, contact pads **161** distributed thereon, the protection layer **162** partially exposing the contact pads **161**, and the connecting pillars **163** penetrating the protection layer **162** and electrically connected to the contact pads **161**.

[0068] In some embodiments, the integrated fan-out package **50b** and the semiconductor chip **160** are encapsulated in the insulating encapsulation **170'**, where top surfaces **163a** of the connecting pillars **163** of the semiconductor chip **160**, top surfaces **150a** of the conductive features **150** of the integrated fan-out package **50b** are substantially leveled with and coplanar to a top surface **170a'** of

the insulating encapsulation **170'**. In some embodiments, the redistribution layer **180** is located on the integrated fan-out package **50b**, the semiconductor chip **160**, and the insulating encapsulation **170'**, and the redistribution layer **180** is electrically connected to the integrated fan-out package **50b** and the semiconductor chip **160** through the conductive features **150** and the connecting pillars **163**, respectively; so that the integrated fan-out package **50b** and the semiconductor chip **160** are electrically communicated to each other through the redistribution layer **180**. With such configuration, a short electrical connection path from the semiconductor chip **160** to the integrated fan-out package **50b** is achieved; the chip package **20** has better electrical performance. In some embodiments, the conductive elements **200** are electrically connected to the redistribution layer **180** through the UBM pattern **190**, where some of the conductive elements **200** are electrically connected to the semiconductor chip **160** through some of the UBM patterns **190** and the redistribution layer **180**, and some of the conductive elements **200** are electrically connected to the integrated fan-out package **50b** through some of the UBM patterns **190** and the redistribution layer **180**. Due to the integrated fan-out package **50b** and the semiconductor chip **160** are both encapsulated in the insulating encapsulation **170'**, a thickness of the chip package **20** is significantly reduced.

[0069] In some embodiments, the processes described in FIG. 1 to FIG. 6 can be substituted with the processes described in the flow chart **40a** of FIG. 18 to form the integrated fan-out package **50b**, and then the previously described manufacturing process as described in FIG. 7 to FIG. 11 above can be performed to form the chip package **20** depicted in FIG. 17. Referring to FIG. 18, at step **41a**, in some embodiments, a carrier is provided. For example, the carrier **C1** is provided. In an alternative embodiment, the debond layer **DB1**, the connecting film **DA2**, and/or the insulating layer (not shown) may be formed on the carrier **C1**, the disclosure is not limited thereto. Referring to FIG. 18, at step **42a**, in some embodiments, a redistribution layer is formed on the carrier. For example, the redistribution layer similar to the redistribution layer **140** depicted in FIG. 5 is formed on the carrier **C1**. Referring to FIG. 18, at step **43a**, in some embodiments, at least one semiconductor chip is disposed on a first side of the redistribution layer. For example, the semiconductor chip **110'** and the semiconductor chip **120'** are picked up and placed on the redistribution layer **140** and over the carrier **C1**. In an alternative embodiment, additional connecting films may be formed between the redistribution layer **140**, the semiconductor chip **110'**, and the semiconductor chip **120'** to enhance the adhesion degree thereof. Referring to FIG. 18, at step **44a**, in some embodiments, at least one connecting wiring is disposed to electrically connect the at least one semiconductor chip to the redistribution layer. For example, the wirings **WR1**, **WR2** are provided and disposed to electrically connect the semiconductor chip **110'** and the semiconductor chip **120'** to the redistribution layer **140**, respectively. Referring to FIG. 18, at step **45a**, in some embodiments, the at least one semiconductor chip and the at least one connecting wiring are encapsulated in an encapsulant. For example, the semiconductor chip **110'**, the semiconductor chip **120'**, and the wirings **WR1**, **WR2** are encapsulated in the encapsulant **130'**. Referring to FIG. 18, at step **46a**, in some embodiments, the carrier is debonded to expose a second side of the redistribution layer, where the second side is opposite to the first side. For example, the carrier **C1** is debonded to expose the redistribution layer **140**, so that a surface of the redistribution layer **140** not contacting the encapsulant **130'** is exposed. Referring to FIG. 18, at step **47a**, in some embodiments, conductive features are formed on the second side of the redistribution layer, where the conductive features are electrically connected to the redistribution layer and exposed by the encapsulant, so that the redistribution layer are located between the encapsulant and the conductive features, and sidewalls of the conductive features are physically contacted to the insulating encapsulation. For example, the conductive features **150** are formed on the surface of the redistribution layer **140** not contacting the encapsulant **130'**, where the conductive features **150** are electrically connected to the redistribution layer **140** and exposed by the encapsulant **130'**, such that the redistribution layer **140** is located between the conductive features **150** and the encapsulant

**130'**, and sidewalls of the conductive features **150** are physically contacted to the insulating encapsulation **170'**. Up to here, the integrated fan-out package **50b** is completed.

[0070] In some embodiments, a chip package **20'** depicted in FIG. **19** is similar to the chip package **20** depicted in FIG. **17**, such that the elements similar to or substantially the same as the elements described above will use the same reference numbers, and certain details or descriptions of the same elements and the relationship thereof (e.g. the relative positioning configuration and electrical connection) will not be repeated herein. Referring to the chip package **20** depicted in FIG. **17** and the chip package **20'** depicted in FIG. **19** together, the chip package **20'** further includes an additional element, a protection layer PL. In some embodiments, the protection layer PL is formed on the integrated fan-out package **50b** to wrap at least sidewalls **150S** of the conductive features **150**. In such embodiments, the top surfaces **150a** of the conductive features **150** and a top surface of the protection layer PL are substantially coplanar with the top surface **170a'** of the insulating encapsulation **170'**, as shown in FIG. **19**. As shown in FIG. **19**, the conductive features **150** of the integrated fan-out package **50b** are not in physical contact with the insulating encapsulation **170'**, for example. Due to the protection layer PL, the conductive features **150** are protected from being damaged during the transferring step of the integrated fan-out package **50b**, and thereby the reliability of electrical connections in the chip package **20'** is further improved.

[0071] FIG. **20** is a schematic cross sectional view illustrating a chip package in accordance with some exemplary embodiments of the present disclosure. FIG. **21** is a flow chart illustrating a method of forming an integrated fan-out package in accordance with some exemplary embodiments of the present disclosure. Referring to FIG. **11** and FIG. **20** together, the chip package **10** depicted in FIG. **11** and the chip package **30** depicted in FIG. **20** are similar; such that the elements similar to or substantially the same as the elements described above will use the same reference numbers, and certain details or descriptions of the same elements and the relationship thereof (e.g. the relative positioning configuration and electrical connection) will not be repeated herein. Referring to FIG. **11** and FIG. **20** together, the difference is that, for the chip package **30** depicted in FIG. **20**, the chip package **30** includes an integrated fan-out package **50c** instead of the integrated fan-out package **50a** included in the chip package **10**.

[0072] In some embodiments, the chip package **30** includes a semiconductor chip **160**, an insulating encapsulation **170'**, a redistribution layer **180**, UBM patterns **190**, and conductive element **200** in addition to the integrated fan-out package **50c**.

[0073] As shown in FIG. **20**, the integrated fan-out package **50c** includes a semiconductor chip **110'**, a semiconductor chip **120'**, an encapsulant **130'**, a semiconductor circuit substrate CB, conductive features **150**, and wirings WR1, WR2. As shown in FIG. **20**, for example, the semiconductor chip **110'** and the semiconductor chip **120'** are disposed on the semiconductor circuit substrate CB, are respectively electrically connected to the semiconductor circuit substrate CB through the wiring WR1 and the wiring WR2, and are encapsulated in the encapsulant **130'**. In some embodiments, the conductive features **150** are disposed on and electrically connected to the semiconductor circuit substrate CB, where the semiconductor circuit substrate CB is located between the conductive features **150** and the encapsulant **130'**. That is, the conductive features **150** are exposed by the encapsulant **130'**. In certain embodiments, through the semiconductor circuit substrate CB, some of the conductive features **150** are electrically connected to the semiconductor chip **110'**, and some of the conductive features **150** are electrically connected to the semiconductor chip **120'**. In certain embodiments, the integrated fan-out package **50c** further includes a connecting film DA1 provided between the semiconductor chip **110'** and the semiconductor chip **120'**, and a connecting film DA2 provided between the semiconductor chip **110'** and the semiconductor circuit substrate CB. Due to the connecting film DA1, the semiconductor chip **120'** is stably adhered to the semiconductor chip **110'**; and due to the connecting film DA2, the semiconductor chip **110'** is stably adhered to the semiconductor circuit substrate CB.

[0074] In some embodiments, the semiconductor chip **160** includes an active surface **160a**, contact

pads **161** distributed thereon, the protection layer **162** partially exposing the contact pads **161**, and the connecting pillars **163** penetrating the protection layer **162** and electrically connected to the contact pads **161**.

[0075] In some embodiments, the integrated fan-out package **50c** and the semiconductor chip **160** are encapsulated in the insulating encapsulation **170'**, where top surfaces **163a** of the connecting pillars **163** of the semiconductor chip **160**, top surfaces **150a** of the conductive features **150** of the integrated fan-out package **50c** are substantially leveled with and coplanar to a top surface **170a'** of the insulating encapsulation **170'**. In some embodiments, the redistribution layer **180** is located on the integrated fan-out package **50c**, the semiconductor chip **160**, and the insulating encapsulation **170'**, and the redistribution layer **180** is electrically connected to the integrated fan-out package **50c** and the semiconductor chip **160** through the conductive features **150** and the connecting pillars **163**, respectively; so that the integrated fan-out package **50c** and the semiconductor chip **160** are electrically communicated to each other through the redistribution layer **180**. With such configuration, a short electrical connection path from the semiconductor chip **160** to the integrated fan-out package **50c** is achieved; the chip package **20** has better electrical performance. In some embodiments, the conductive elements **200** are electrically connected to the redistribution layer **180** through the UBM pattern **190**, where some of the conductive elements **200** are electrically connected to the semiconductor chip **160** through some of the UBM patterns **190** and the redistribution layer **180**, and some of the conductive elements **200** are electrically connected to the integrated fan-out package **50c** through some of the UBM patterns **190** and the redistribution layer **180**. Due to the integrated fan-out package **50c** and the semiconductor chip **160** are both encapsulated in the insulating encapsulation **170'**, a thickness of the chip package **30** is significantly reduced.

[0076] In some embodiments, the processes described in FIG. 1 to FIG. 6 can be substituted with the processes described in the flow chart **40b** of FIG. 21 to form the integrated fan-out package **50c**, and then the previously described manufacturing process as described in FIG. 7 to FIG. 11 above can be performed to form the chip package **30** depicted in FIG. 20.

[0077] Referring to FIG. 21, at step **41b**, in some embodiments, a semiconductor circuit substrate is provided. For example, a semiconductor circuit substrate CB is provided. In one embodiment, the semiconductor circuit substrate CB may be a printed circuit board (PCB), or an organic substrate having an interconnection circuit structure therein, the disclosure is not limited thereto. Referring to FIG. 21, at step **42b**, in some embodiments, at least one semiconductor chip is disposed on the semiconductor circuit substrate. For example, the semiconductor chip **110'** and the semiconductor chip **120'** are picked up and placed on the semiconductor circuit substrate CB. In an alternative embodiment, additional connecting films may be formed between the semiconductor circuit substrate CB, the semiconductor chip **110'**, and the semiconductor chip **120'** to enhance the adhesion degree thereof. Referring to FIG. 21, at step **43b**, in some embodiments, at least one connecting wiring is disposed to electrically connect the at least one semiconductor chip to the semiconductor circuit substrate. For example, the wirings **WR1**, **WR2** are provided and disposed to electrically connect the semiconductor chip **110'** and the semiconductor chip **120'** to the semiconductor circuit substrate CB, respectively. Referring to FIG. 21, at step **44b**, in some embodiments, the at least one semiconductor chip and the at least one connecting wiring are encapsulated in an encapsulant. For example, the semiconductor chip **110'**, the semiconductor chip **120'**, and the wirings **WR1**, **WR2** are encapsulated in the encapsulant **130'**. Referring to FIG. 21, at step **45b**, conductive features are formed on the semiconductor circuit substrate, where the conductive features are electrically connected to the semiconductor circuit substrate and exposed by the encapsulant, so that the semiconductor circuit substrate are located between the encapsulant and the conductive features, and sidewalls of the conductive features are physically contacted to the insulating encapsulation. For example, the conductive features **150** are formed on the surface of the semiconductor circuit substrate CB not contacting the encapsulant **130'**, where the conductive



features **150** are electrically connected to the semiconductor circuit substrate CB and exposed by the encapsulant **130'**, such that the semiconductor circuit substrate CB is located between the conductive features **150** and the encapsulant **130'**, and sidewalls of the conductive features **150** are physically contacted to the insulating encapsulation **170'**. Up to here, the integrated fan-out package **50c** is completed.

[0078] In some embodiments, a chip package **30'** depicted in FIG. **22** is similar to the chip package **30** depicted in FIG. **20**, such that the elements similar to or substantially the same as the elements described above will use the same reference numbers, and certain details or descriptions of the same elements and the relationship thereof (e.g. the relative positioning configuration and electrical connection) will not be repeated herein. Referring to the chip package **30** depicted in FIG. **20** and the chip package **30'** depicted in FIG. **22** together, the chip package **30'** further includes an additional element, a protection layer PL. In some embodiments, the protection layer PL is formed on the integrated fan-out package **50c** to wrap at least sidewalls **150S** of the conductive features **150**. In such embodiments, the top surfaces **150a** of the conductive features **150** and a top surface of the protection layer PL are substantially coplanar with the top surface **170a'** of the insulating encapsulation **170'**, as shown in FIG. **22**. As shown in FIG. **22**, the conductive features **150** of the integrated fan-out package **50c** are not in physical contact with the insulating encapsulation **170'**, for example. Due to the protection layer PL, the conductive features **150** are protected from being damaged during the transferring step of the integrated fan-out package **50c**, and thereby the reliability of electrical connections in the chip package **30'** is further improved.

[0079] In accordance with some embodiments, a chip package includes a redistribution layer, at least one first semiconductor chip, an integrated fan-out package, and an insulating encapsulation. The at least one first semiconductor chip and the integrated fan-out package are electrically connected to the redistribution layer, wherein the at least one first semiconductor chip and the integrated fan-out package are located on a surface of the redistribution layer and electrically communicated to each other through the redistribution layer, and wherein the integrated fan-out package includes at least one second semiconductor chip. The insulating encapsulation encapsulates the at least one first semiconductor chip and the integrated fan-out package.

[0080] In accordance with some embodiments, a chip package includes a redistribution layer, at least one first semiconductor chip, an integrated fan-out package, and an insulating encapsulation. The at least one first semiconductor chip and the integrated fan-out package are electrically connected to the redistribution layer, wherein the at least one first semiconductor chip and the integrated fan-out package are located on a surface of the redistribution layer and electrically communicated to each other through the redistribution layer. The integrated fan-out package includes a redistribution circuit structure, at least one second semiconductor chip and at least third semiconductor chip located on and electrically connected to the redistribution circuit structure, an encapsulant encapsulating the at least one second semiconductor chip and the at least third semiconductor chip, and conductive features located on and electrically connected to the redistribution circuit structure. The redistribution circuit structure is located between the encapsulant and the conductive features. The insulating encapsulation, encapsulating the at least one first semiconductor chip and the integrated fan-out package.

[0081] In accordance with some embodiments, a manufacturing method of a chip package is provided with the following steps: providing a first carrier; disposing at least one first semiconductor chip and an integrated fan-out package on the first carrier, the integrated fan-out package including at least one second semiconductor chip; encapsulating the at least one first semiconductor chip and the integrated fan-out package in an insulating encapsulation; forming a redistribution layer on the insulating encapsulation, the redistribution layer being electrically connected to the at least one first semiconductor chip and the integrated fan-out package, wherein the at least one first semiconductor chip and the integrated fan-out package are arranged side-by-side and on a surface of the redistribution layer; disposing conductive elements on the

redistribution layer, wherein the redistribution layer is located between the insulating encapsulation and the conductive elements; and debonding the first carrier.

[0082] In accordance with some embodiments, a chip package includes a redistribution layer, at least one first semiconductor chip, an integrated fan-out package and an insulating encapsulation. The at least one first semiconductor chip and the integrated fan-out package are located on a surface of the redistribution layer and electrically communicated to each other therethrough, and wherein the integrated fan-out package comprises second semiconductor chips and a redistribution circuit structure, wherein the redistribution circuit structure is located between and electrically connected to the second semiconductor chips and the redistribution layer. The insulating encapsulation encapsulates the at least one first semiconductor chip and the integrated fan-out package and covers a sidewall of the redistribution circuit structure.

[0083] In accordance with some embodiments, a chip package includes a redistribution layer, at least one first semiconductor chip, an integrated fan-out package and an insulating encapsulation. The at least one first semiconductor chip and the integrated fan-out package are located on a surface of the redistribution layer and electrically communicated to each other therethrough, and wherein the integrated fan-out package includes a redistribution circuit structure, at least one second semiconductor chip and at least third semiconductor chip, wherein the at least one second semiconductor chip and the at least third semiconductor chip are located at a side of and electrically connected to the redistribution circuit structure. The insulating encapsulation encapsulates the at least one first semiconductor chip and the integrated fan-out package.

[0084] In accordance with some embodiments, a manufacturing method of a chip package is provided with the following steps: providing a first carrier; disposing at least one first semiconductor chip and an integrated fan-out package on the first carrier, the integrated fan-out package comprising second semiconductor chips and a redistribution circuit structure located between and electrically connected to the second semiconductor chips and the redistribution layer; encapsulating the at least one first semiconductor chip and the integrated fan-out package in an insulating encapsulation, a sidewall of the redistribution circuit structure being covering by the insulating encapsulation; forming a redistribution layer on the insulating encapsulation, the redistribution layer being electrically connected to the at least one first semiconductor chip and the integrated fan-out package, wherein the at least one first semiconductor chip and the integrated fan-out package are arranged side-by-side and on a surface of the redistribution layer, and the at least one first semiconductor chip and the integrated fan-out package are electrically communicated to each other through the redistribution layer; disposing conductive elements on the redistribution layer, wherein the redistribution layer is located between the insulating encapsulation and the conductive elements; and debonding the first carrier.

[0085] The foregoing outlines features of several embodiments so that those skilled in the art may better understand the aspects of the present disclosure. Those skilled in the art should appreciate that they may readily use the present disclosure as a basis for designing or modifying other processes and structures for carrying out the same purposes and/or achieving the same advantages of the embodiments introduced herein. Those skilled in the art should also realize that such equivalent constructions do not depart from the spirit and scope of the present disclosure, and that they may make various changes, substitutions, and alterations herein without departing from the spirit and scope of the present disclosure.

## Claims

1. A chip package, comprising: an integrated circuit component, comprising: a redistribution circuit structure; and a plurality of first semiconductor dies, disposed at a side of and electrically connected to the redistribution circuit structure; a second semiconductor die, comprising an active surface and a rear surface opposite to the active surface, and arranged next to the integrated circuit

- component in a horizontal direction; and an insulating encapsulation, encapsulating the integrated circuit component and the second semiconductor die, wherein a sidewall of the redistribution circuit structure and a sidewall of the second semiconductor die are covered by the insulating encapsulation, wherein a first surface of the insulating encapsulation is substantially coplanar to the active surface of the second semiconductor die.
2. The chip package of claim 1, wherein the plurality of first semiconductor dies are free of the insulating encapsulation through an encapsulant of the integrated circuit component, and a sidewall of the encapsulant are covered by the insulating encapsulation.
  3. The chip package of claim 2, wherein the sidewall of the encapsulant is substantially aligned with the sidewall of the redistribution circuit structure.
  4. The chip package of claim 1, wherein at least one of the plurality of first semiconductor dies is electrically connected to the redistribution circuit structure through conductive wires.
  5. The chip package of claim 1, wherein at least one of the plurality of first semiconductor dies is electrically connected to the redistribution circuit structure through conductive pillars.
  6. The chip package of claim 1, further comprising: a redistribution structure, disposed on the insulating encapsulation and electrically coupled to the plurality of the first semiconductor dies and the second semiconductor die, wherein a sidewall of the redistribution structure is substantially aligned with a sidewall of the insulating encapsulation.
  7. The chip package of claim 6, further comprising: a plurality of conductive terminals, disposed on and electrically coupled to the redistribution structure, wherein the redistribution structure is disposed between the plurality of conductive terminals and the insulating encapsulation.
  8. The chip package of claim 1, wherein the integrated circuit component further comprises: a plurality of conductive terminals, disposed on and electrically coupled to the redistribution circuit structure, wherein the redistribution circuit structure is disposed between the plurality of conductive terminals and the plurality of first semiconductor dies.
  9. A chip package, comprising: an integrated circuit component, comprising: a redistribution circuit structure; a plurality of first semiconductor dies, disposed at a side of and electrically connected to the redistribution circuit structure; and a first insulating encapsulation, encapsulating the plurality of first semiconductor dies, wherein sidewalls of the plurality of first semiconductor dies are covered by the first insulating encapsulation; a second semiconductor die, arranged next to the integrated circuit component in a horizontal direction; and a second insulating encapsulation, encapsulating the integrated circuit component and the second semiconductor die, wherein a sidewall of the first insulating encapsulation, a sidewall of the redistribution circuit structure and a sidewall of the second semiconductor die are covered by the second insulating encapsulation.
  10. The chip package of claim 9, wherein the plurality of first semiconductor dies are free of the second insulating encapsulation through the first insulating encapsulation, and the sidewall of the first insulating encapsulation is substantially aligned with the sidewall of the redistribution circuit structure.
  11. The chip package of claim 9, wherein at least one of the plurality of first semiconductor dies is electrically connected to the redistribution circuit structure through a conductive wire.
  12. The chip package of claim 9, wherein at least one of the plurality of first semiconductor dies is electrically connected to the redistribution circuit structure through a conductive pillar.
  13. The chip package of claim 9, further comprising: a redistribution structure, disposed on the second insulating encapsulation and electrically coupled to the plurality of the first semiconductor dies and the second semiconductor die, wherein a sidewall of the redistribution structure is substantially aligned with a sidewall of the second insulating encapsulation.
  14. The chip package of claim 13, further comprising: a plurality of conductive terminals, disposed on and electrically coupled to the redistribution structure, wherein the redistribution structure is disposed between the plurality of conductive terminals and the second insulating encapsulation.
  15. The chip package of claim 9, wherein the integrated circuit component further comprises: a

plurality of conductive terminals, disposed on and electrically coupled to the redistribution circuit structure, wherein the redistribution circuit structure is disposed between the plurality of conductive terminals and the plurality of first semiconductor dies.

**16.** A chip package, comprising: an integrated circuit component, comprising: a redistribution circuit structure; a plurality of first semiconductor dies, disposed at a side of the redistribution circuit structure and stacked on one another in a vertical direction; a first insulating encapsulation, encapsulating the plurality of first semiconductor dies, wherein sidewalls of the plurality of first semiconductor dies are covered by the first insulating encapsulation; and a plurality of conductive terminals, disposed on the redistribution circuit structure, wherein the redistribution circuit structure is disposed between the plurality of conductive terminals and the plurality of first semiconductor dies; a second semiconductor die, arranged next to the integrated circuit component in a horizontal direction; and a second insulating encapsulation, encapsulating the integrated circuit component and the second semiconductor die.

**17.** The chip package of claim 16, wherein the plurality of first semiconductor dies are free of the second insulating encapsulation through the first insulating encapsulation, and a sidewall of the first insulating encapsulation and a sidewall of the redistribution circuit structure are substantially aligned and are covered by the second insulating encapsulation.

**18.** The chip package of claim 16, wherein at least one of the plurality of first semiconductor dies is electrically connected to the redistribution circuit structure through a conductive wire or a conductive pillar.

**19.** The chip package of claim 16, further comprising: a redistribution structure, disposed on the second insulating encapsulation and electrically coupled to the plurality of the first semiconductor dies and the second semiconductor die, wherein a sidewall of the redistribution structure is substantially aligned with a sidewall of the second insulating encapsulation.

**20.** The chip package of claim 16, further comprising: a plurality of terminals, disposed on and electrically coupled to the redistribution structure, wherein the redistribution structure is disposed between the plurality of terminals and the second insulating encapsulation.

---